

Auto-correlation. An initial analysis of the distribution of the slow-on and slow-off states' survival times showed an exponential decay with time, indicating a stochastic process¹. However, the lifetimes of the fast-on and fast-off states were examined using the higher time-resolution technique (higher even than the sampling rate) of auto-correlation² of the time-resolved current measurements $I(t)$,

$$g^{(2)}(\delta) = \langle I(t)I(t+\delta) \rangle / \langle I(t) \rangle^2.$$

Knowing that the distribution of survival times for both states is exponential, the auto-correlation was modelled by,

$$g^{(2)}(\delta) = 1 + C \exp[-(1/\tau_{on} + 1/\tau_{off})\delta],$$

with τ_{on} and τ_{off} the lifetimes of the on- and off-states.²

With well defined on- and off-states the contrast $C = (I_{on} - I_{off})^2 / [\tau_{on} \tau_{off} (I_{on}/\tau_{on} + I_{off}/\tau_{off})]$ with I_{on} and I_{off} the tunnelling current values determined from the Gaussian fits to the current distributions. Within experimental error, both the auto-correlation and the distribution of survival time analysis gave the same lifetime values for the on-state and off-states for the slow-switch.

When only one state was well defined the other state's tunnelling current value, for example, I_{on} was substituted by $(\tau_{off} I_{off} + I_{Average} \tau_{on} \tau_{off}) / \tau_{on}$ where $I_{Average}$ is the average tunnelling current over the whole time-trace. From the resulting lifetime values the unknown tunnelling current was calculated.

References

¹ Lastapis, M.; Martin, M.; Riedel, D.; Hellner, L.; Comtet, G.; Dujardin, G. *Science* **2005**, *308*, 1000.

² Zumbusch, A.; Fleury, L.; Brown, R.; Bernard, J.; Orrit, M. *Phys. Rev. Lett.* **1993**, *70*, 3584.